

IEEE Computer Society

TTTC: Test Technology Technical Council

PURPOSE: The Test Technology Technical Council (TTTC) is a volunteer professional organisation sponsored by the IEEE Computer Society. The goals of TTTC are to contribute to member's professional development and advancement and to help them solve engineering problems in electronic test, and help advance the state-of-the art. All activities are led by volunteer members.

MEMBERSHIP: TTTC membership is open to all individuals interested in test engineering at a professional level. In addition to the benefits of personal association with other test professionals and the opportunity to serve on a wide range of committees, members receive TTTC Newsletters and announcements.

DUES: There are NO dues for TTTC membership and no parent-organisation membership requirements; however there are substantial reductions in fees for TTTC-sponsored meetings and tutorials for members of IEEE and/or IEEE Computer Society (IEEE and IEEE/CS do have member fees).

NEWSLETTER: Every year TTTC publishes four issues of its newsletter embedded in the magazine IEEE Design & Test of Computers. In addition TTTC publishes several issues of a more comprehensive newsletter that is mailed to all members. The newsletter covers current issues in test, TTTC technical activities, standards, technical meetings, etc.

STANDARDS: TTTC initiates nurtures and encourages new test standards. TTTC-initiated Working Groups have produced numerous IEEE standards, including the 1149 series used throughout the industry.

TECHNICAL ACTIVITIES: TTTC sponsors a number of Technical Activity Committee (TACs) that address emerging test technology topics. TTTC TACs guide a wide range of activities in these topic areas.

TECHINICAL MEETINGS: TTTC sponsors several well-known conferences and symposia and holds numerous regional and topical workshops to spread technical knowledge and advance the state-of-the art.

TUTORIALS and EDUCATION: TTTC sponsors a comprehensive *Test Technology Educational Program (TTEP)*. This program provides opportunities for design and test professionals to update and expand their knowledge base in test technology, and earn official accreditation from IEEE TTTC, upon the completion of four full day tutorials offered by TTEP. TTEP tutorials are held in conjunction with ITC, VTS, ATS, ETW, and DFTS.

TTTC On-Line: The TTTC Web Site at <http://computer.org/tttc> offers samples of the TTTC Newsletter, information about technical activities, conferences, workshops and standards, and link to the Web pages of a number of TTTC-sponsored technical meetings.

TTTC Officers for 1999

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Technical Activity Committees

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<i>Verification & Test</i>	Jacob A. ABRAHAM	University of Texas at Austin	jaa@cerc.utexas.edu

Standards Working Groups

<i>IEEE 1149.1</i>	Christopher J. CLARK	Intellitech Corporation	cjclark@intellitech.com
<i>IEEE 1149.5</i>	Harry HULVERSHORN	LogicVision, Inc.	harryh@logicvision.com
<i>IEEE P1149.4</i>	Adam CRON	Synopsys, Inc.	acron@synopsys.com
<i>IEEE 1450 - (STIL)</i>	Gregory MASTON	Fluence	gregm@fluence.com
	Tony TAYLOR	Fluence	tonyt@fluence.com
<i>IEEE P1500</i>	Yervant ZORIAN	LogicVision, Inc.	zorian@logicvision.com
<i>IEEE P1532</i>	Neil JACOBSON	Xilinx Corp.	neil.jacobson@xilinx.com

TTC sponsored Technical Meetings in 1999

Feb 23-26	<i>Pacific Northwest Test Workshop</i>	Botega Bay, CA - USA	E. J. McCLUSKEY
Feb 28 - Mar 02	<i>TWS'99 German Workshop</i>	Potsdam - Germany	H. T. VIERHAUS
Mar 9-12	<i>D.A.TE'99</i>	Munich - Germany	R. ERNST
Mar 22-24	<i>Test Synthesis Workshop</i>	Santa Barbara, CA - USA	R. C. AITKEN
Mar 30 - Apr 01	<i>Design, Test of MEMS/MOEMS</i>	Paris - France	B. COURTOIS
Apr 25	<i>IDDQ Testing Mini-Workshop</i>	Dana Point, CA - USA	Y. K. MALAIYA
Apr 25-29	<i>VLSI Test Symposium</i>	Dana Point, CA - USA	M. NICOLAIDIS
Apr 28-29	<i>Testing Embedded Cores Workshop</i>	Dana Point, CA - USA	Y. ZORIAN
May 19-21	<i>Signal Propagation Workshop</i>	Titisee-Neustadt - Germany	J. P. MUCHA
May 25-28	<i>European Test Workshop</i>	Constance - Germany	H.-J. WUNDERLICH
May 27-28	<i>North Atlantic Test Workshop</i>	West Greenwich, RI - USA	J.-C. LO
Jun 06-09	<i>Southwest Test Workshop</i>	San Diego, CA - USA	W. R. MANN
Jun 15-18	<i>Mixed Signal Testing Workshop</i>	British Columbia - Canada	A. IVANOV
Jun 16-18	<i>Rapid System Prototyping</i>	Clearwater, FL - USA	R. LAUWEREINS
Jul 05-07	<i>On-Line Testing Workshop</i>	Rhodes - Greece	M. NICOLAIDIS
Aug 05-06	<i>VLSI Design & Test Workshops</i>	New Delhi - India	C. P RAVIKUMAR
Aug 09-10	<i>Memory Test Workshop</i>	San Jose, CA - USA	R. RAJSUMAN
Aug 17-22	<i>Computer Science Conference</i>	Yerevan - Armenia	Y. SHOUKOURIAN
Sep 06-08	<i>Electronic Systems Conference</i>	Bratislava - Slovakia	D. DONOVAL
Sep 12-15	<i>High Density Module Test VI</i>	Napa, CA - USA	R. J. WAGNER
Sep 15-17	<i>Known Good Die Industry Workshop</i>	Napa, CA - USA	L. GILG
Sep 28-30	<i>International Test Conference</i>	Atlantic City, NJ - USA	M. TOPSAKAL
Sep 30 - Oct 01	<i>Production Test Automation Workshop</i>	Atlantic City, NJ - USA	A. P. AMBLER
Sep 30 - Oct 01	<i>Microprocessor Test Workshop</i>	Atlantic City, NJ - USA	M. S. ABADIR
Sep 30 - Oct 01	<i>System Test and Diagnosis Workshop</i>	Atlantic City, NJ - USA	R. W. SIMPSON
Oct 04-06	<i>Thermal Investigations of ICs Workshop</i>	Rome - Italy	B. COURTOIS
Oct 25-27	<i>1999 DAK Forum</i>	Trondheim - Norway	E. J. AAS
Nov 01-03	<i>Defect & Fault Tolerance Symposium</i>	Albuquerque, NM - USA	C. METRA
Nov 04-06	<i>High-Level Design Validation Test W.</i>	San Diego, CA - USA	A. ORAILOGLU
Nov 16-18	<i>Asian Test Symposium</i>	Shanghai - China	B. M. Y. HSIAO

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